Issue Classification



Application/Control No.	Applicant(s)/Patent Under Reexamination						
08471890	HUFFMAN ET AL.						
Examiner	Art Unit						
DAH-WEI YUAN	1717						

ORIGINAL							INTERNATIONAL CLASSIFICATION								
CLASS SUBCLASS					CLAIMED						NON-CLAIMED				
423 445B			С	0	1	В	31 / 02 (2006.0)								
CROSS REFERENCE(S)						С	0	1	В	31 / 00 (2006.0)					
CLASS SUBCLASS (ONE SUBCLASS PER BLOCK)				OCK)											
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	Claims renumbered in the same order as presented by applicant								CF	A D] T.D.	☐ R.1.47			
Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original
1	122	17	142	33	159										
2	123	18	143	34	160										
3	124	19	144	35	161										
4	126	20	145	36	162										
5	127	21	146	37	163										
6	130	22	147	38	164										
7	131	23	148	39	165										
8	133	24	149												
9	134	25	150												
10	135	26	151												
11	136	27	153												
12	137	28	154												
13	138	29	155												
14	139	30	156												
15	140	31	157												
16	141	32	158												

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(Assistant Examiner)	(Date)	39				
/DAH-WEI YUAN/ Supervisory Patent Examiner.Art Unit 1717	09/08/2011	O.G. Print Claim(s)	O.G. Print Figure			
(Primary Examiner)	(Date)	1	2			

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